### i-Labs

## **Device Characterization Lab**

In this lab exercise, you will obtain the current-voltage characteristics of an npn bipolar junction transistor (BJT) and an n-MOSFET. To do this, you will use the MIT Microelectronics WebLab. The npn BJT is available is device 3 of WebLab and the nMOSFET is device 2 on the devices menu. The i-labs can be accessed at <a href="http://emuklabs.mak.ac.ug">http://emuklabs.mak.ac.ug</a>. Use the account you created last semester- in case you do not have one or you forgot your password, please send an email to alumu@tech.mak.ac.ug.

Take the measurements specified below. When you are happy with the results (as judged by the characteristics displayed through the web), download the data to your local machine for more graphing and further analysis in MS Excel. (A tutorial on this is available at the Intranet site <a href="http://fot/weblab/weblabbjt.pdf">http://fot/weblab/weblabbjt.pdf</a>)

## Note:

Do not use voltages higher than 3.0V for the  $V_{CE}$  (common-emitter voltage), and  $V_{GS}$  (gate-to-source voltage). Use  $V_{GS}$  in the range 2.0V $\leq V_{GS} \geq 3.0V$ . The base-emitter voltage,  $V_{BE}$  (base-emitter voltage) should not exceed 0.9V, otherwise the device may be damaged.

Values of the base current,  $I_{B}$  greater than 60µA should not be used as they will strain the device.

# Part I

Obtain I-V characteristics for the BJT and the NMOS transistor.

Measure  $I_D$  (drain current) vs.  $V_{DS}$  (drain-to-source voltage) with  $V_{GS}$  as a parameter. For the BJT, measure  $I_C$  (collector current) vs.  $V_{CE}$  as a function of various  $I_B$  (base current).

Show your measurement results in the following graphs:

*Graph 1*: <u>Output characteristics</u> of the BJT,  $I_c$  vs.  $V_{cE}$ , for different values of  $I_B$ . For this graph, indicate the 3 regions of operation of a BJT, namely:

- 1. Linear
- 2. Cutoff
- 3. Saturation

Note down the temperature of the BJT.

*Graph 2*: The output characteristics of the nMOS,  $I_D$  vs.  $V_{DS}$ , for different values of  $V_{GS}$ . Indicate the ohmic and active regions of this nMOS. Note down the temperature of this device too.

*Graph 3*: Obtain the transfer characteristics of the NMOS ( $V_{GS}$  vs  $I_{DS}$ ) for various values of  $V_{DS}$ . From this plot, approximate the value of  $V_{T}$ , the threshold (sometimes called the pinch off) voltage. From your approximate value for  $V_{T}$ , what type (mode) of nMOSFET is this?

Graph 4: For the BJT, plot  $I_c$  vs.  $V_{\text{\tiny BE}}$ , for different values of  $V_{\text{\tiny CE}}$ .

Graph 5: For the BJT, plot  $I_{B}$  vs.  $V_{BE}$ , for different values of  $V_{CE}$ .

i-Labs

### Part II :Small signal graphs.

The the output resistance of the nMOS is defined by  $r_{oNMOS} = \frac{dV_{DS}}{dI_{DS}}$  (at a fixed V<sub>GS</sub> value); that of the BJT by  $r_{oBJT} = \frac{dV_{CE}}{dI_{C}}$  (at a fixed value of I<sub>B</sub>).

The BJT's transconductance,  $g_m$  is given by the equation  $g_m = \frac{dI_C}{dV_{BE}}$ .

For this part you will need to use the DELTA inbuilt function for most of the measurements hereconsult the Weblab manual at the Intranet site: <u>http://fot/weblab/User\_Manual\_Draft2.pdf</u>)

Graph 6: plot the output resistance ( $r_{oNMOS}$ ) of the NMOS as a function of  $V_{DS}$ , for different values of  $V_{GS}$ .

*Graph* 7: plot the output resistance  $(r_{\text{\tiny OBJT}})$  of the BJT as a function of  $V_{\text{CE}}$ , for different values of  $I_{\text{B}}$ . (Use a log scale for  $r_{\text{\tiny OBJT}}$ )

Graph 8: plot the transconductance ( $g_m$ ) of the BJT as a function of  $I_B$ , for  $V_{CE} = 1.5$  V.

### Summary

Any comments related to this exercise such connection speeds, timeouts, access to computers, clarity, difficulty in using the Java Client Applet, etc are all welcome. You can put them in writing or send them by email to the Weblab TA, Albert: <a href="mailto:alumu@tech.mak.ac.ug">alumu@tech.mak.ac.ug</a>.

Your work should be handed in no later than <u>5:00pm Thursday</u>, 2<sup>nd</sup> June 2005.